Sheet 1 of 1 ATTY DOCKET NO. SERIAL NO. FORM PTO 1449 (modified) 2002_0306A **NEW** U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE **APPLICANT** Takashi YAZAWA et al. LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) FILING DATE GROUP March 1, 2002 Date Submitted to PTO: March 1, 2002 U.S. PATENT DOCUMENTS *EXAMINER DOCUMENT DATE NAME CLASS SUBCLASS FILING DATE IF INITIAL NUMBER APPROPRIATE AA AB AC AD ΑE AF AG AH ΑI FOREIGN PATENT DOCUMENTS DOCUMENT SUBCLASS TRANSLATION DATE COUNTRY CLASS NUMBER YES NO 9-246794 AJ 9/1997 JP Abstr. AK 8-8600 1/1996 JP Abstr. AL 8-32299 2/1996 JΡ Abstr. **AM** AN OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.) AO AP

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